

2024 International Symposium on Semiconductor Manufacturing Intelligence (ISMI 2024)

Date: November 29, 2024

Place: Room 442, 4th Floor, Hung Yu Tech & Research Building

Session I	
Session Time: 13:30~14:50	
Session Chair: Prof. You-Jin Park	
Paper Title	Authors
Master Planning for Semiconductor Fabrication Considering Order Stability	Tzu-Han, Kung, Yung-Chia, Chang, Jonathan Yung-Cheng, Chang
A Three-stage DEA Model for Supply Chain Performance Measurement	Xu Wang, Qian Huang, Takashi Hasuike
A Tool Allocation Method for Minimizing the Number of Tool Switches	Hiroaki Ueno, Kotomichi Matsuno, Ruriko Watanabe, Yoshitaka Tanimizu
Application of Integrated Gradients to a Work Anomaly Detection System using Biometric Information	Atsushi Ida, Ruriko Watanabe, Kotomichi Matsuno, Yoshitaka Tanimizu
Optimal Transport Scheduling for Unmanned Vehicles Considering Charging Time	Yongjoo Chung, Chunhyun Paik, Young Jin Kim
Master Planning for Semiconductor Fabrication Considering Order Stability	Tzu-Han, Kung, Yung-Chia, Chang, Jonathan Yung-Cheng, Chang

Session II	
Session Time: 15:20~16:40	
Session Chair: Prof. Kotomichi Matsuno	
Paper Title	Authors
A Spatial-contextual Deep Learning Approach for Enhanced Latent Defect Chip Detection in Semiconductor Fabrication	Young-Mok Bae, Kwang-Jae Kim
Optimal Transport Scheduling for Autonomous Mobile Robots Considering Realistic Charging Time	Hiroyuki Hayase, Hiroaki Ueno, Kotomichi Matsuno, Ruriko Watanabe, Yoshitaka Tanimizu
A metaphor-based robot programming approach to computational thinking	Kuo-Yi Lin, Yeh Shih-Cheng, Yu-Lun Shih, Kuan-Yi Liou, Chia-Lien Chou
Enhancing Semiconductor Yield Prediction with a Dual-View Approach: A Case Study Combining Equipment Usage and Accumulated Cycle Time Data	Young-Mok Bae, Kwang-Jae Kim
A Spatial-contextual Deep Learning Approach for Enhanced Latent Defect Chip Detection in Semiconductor Fabrication	Young-Mok Bae, Kwang-Jae Kim

Session III**Session Time: 16:40~18:00****Session Chair: Prof. Kuo-Yi Lin**

Paper Title	Authors
A Heuristic Approach through Hierarchical Clustering for Large-scale Tool Switching Problem	Shutaro Murata, Hiroaki Ueno, Ruriko Watanabe, Kotomichi Matsuno, Yoshitaka Tanimizu
Dynamic Pricing with Multiple Expiry Dates Based on Prospect Theory	Tasuke Amaya, Shunichi Ohmori
"Case study of business impact of developer-centric MCU	TAKASU Masakazu, AKITA Junichi, OOMORI Shunichi, MAKI Kanetaka, KITO Tomomi
platforms: Comparative Insights from Arduino and M5Stack"	Junichi Akita
NDA-Free Process Design Kit for Matured Fabrication Process	Teppei Hosoya, Kotomichi Matsuno, Yoshikuni Edagawa, Takaaki Kawanaka, Shinya Takata, Yasutaka Kainuma, Kim Hua Tan, Takahiro Ohno